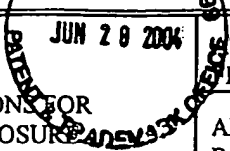


FORM PTO-1449 (Modified)				ATTY. DOCKET NO. IS920030247US1		SERIAL NO. 10/605,672						
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT				APPLICANT: Bruce B. Doris, et al.								
				(Use several sheets if necessary)		FILING DATE: 10/16/03		GROUP: 2812				
REFERENCE DESIGNATION U.S. PATENT DOCUMENTS												
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)						
SDI	6,228,694 B1	5/8/2001	Doyle et al.	X	X	X						
	6,406,973 B1	6/18/2002	Lee									
	6,281,532 B1	8/28/2001	Doyle et al.									
	5,683,934	11/4/97	Candelaria									
	6,368,931 B1	4/9/2002	Kuhn, et al.									
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	6,506,652	01/14/03	Jan, et al.									
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		DOCUMENT NUMBER	DATE					COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)												
EXAMINER <i>Stanley Baac</i>				DATE CONSIDERED <i>4/30/05</i>								
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	6,046,464	4/4/2000	Schetzina			
	6,025,280	2/15/2000	Brady, et al.			

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	5,592,018	1/7/1997	Leedy			
	5,592,007	1/7/1997	Leedy			
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SJF	5,557,122	9/17/1996	Shrivastava, et al.			
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	2001/0009784	07-26-2001	Ma et al.			

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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT

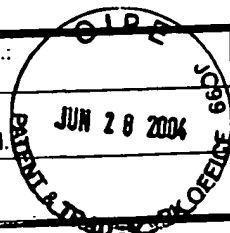
Applicant:
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			K. Ota, et al., "Novel Locally Strained Channel Technique for high Performance 55nm CMOS", International Electron Devices Meeting, 2.2.1, IEEE, February 2002.

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